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	No.1	Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation <sup>6</sup>		
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			OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
i	Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.						
	PAR		NOGUCHI et al., "TDDB Improvement in Cu Metallization under Bias Stress", IEEE, 38 <sup>th</sup> Annual International Reliability Physics Symposium, San Jose, CA, 2000, pp. 339-343						

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